## MT3275

# N-Channel Power MOSFET 75V, 190A, 3.0m $\Omega$

#### **Features**

- Max  $R_{DS(on)}$  = 3.0m $\Omega$  at  $V_{GS}$  = 10V,  $I_D$  = 75A
- · Fast Switching Speed
- · Low Gate Charge
- High Performance Trench Technology for Extr emely Low  $R_{\text{DS}(\text{on})}$
- · High Power and Current Handling Capability
- RoHS Compliant

#### **General Description**

This N-Channel MOSFET is produced using MOS-TECH Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

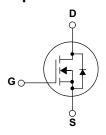
#### **Applications**

- · DC-DC primary bridge
- · DC-DC Synchronous rectification
- Hot swap

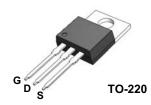


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#### Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



### MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol		Parameter			Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage			75	V	
V <sub>GSS</sub>	Gate to Source Vo	oltage			±25	V
	Drain Curren - Continuous (Silicon Limited) T <sub>C</sub> = 25°C			190		
	- Continuous( Package Limited)			) T <sub>C</sub> = 25°C	120	Α
l <sub>D</sub>	- Continuous T <sub>C</sub> = 25°C(Note 1			$T_C = 25^{\circ}C(Note 1a)$	75	
	- Pulsed			730	Α	
E <sub>AS</sub>	Single Pulsed Ava	alanche Energy		(Note 3)	1300	mJ
Б	Dawer Dissination		- T <sub>C</sub> = 25°C	(Note 1a)	298	W
$P_{D}$	Power Dissipation - T <sub>A</sub> = 25°C		- T <sub>A</sub> = 25°C	(Note 1b)	2.4	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Sto	orage Temperat	ure Range		-55 to +175	°C

#### **Thermal Characteristics**

Symbol	Parameter	Ratings	Units	
$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	0.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	62.5	-0/00

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
MT3275	MT3275	TO-220	-	-	50

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### **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	teristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_C = 25^{\circ} C$	75	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.07	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V	-	-	1	μА
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA

#### On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 75A	-	3.0	4.0	mΩ
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10V, I <sub>D</sub> = 75A	-	167	-	S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	\\ - 25\\ \\ - 2\\	-	17280	-	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V f = 1MHz		1055	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	I - IIVIHZ	-	631	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	89	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>DS</sub> = 80V, I <sub>D</sub> = 75A	-	27	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	V <sub>GS</sub> = 10V	-	8	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		-	60	-	nC

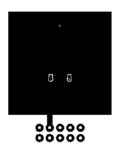
#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 50V, I <sub>D</sub> = 75A V <sub>GS</sub> = 10V, R <sub>GEN</sub> = 4.7Ω	-	22	54	ns
t <sub>r</sub>	Turn-On Rise Time		-	54	118	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		-	37	84	ns
t <sub>f</sub>	Turn-Off Fall Time		-	11	32	ns

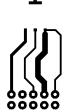
#### **Drain-Source Diode Characteristics**

$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 75A (Note 2)	-	-	1.25	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0V, I_{SD} = 75A, V_{DD} = 80V$	-	72	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	129	-	nC

1. R<sub>0,1A</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,1C</sub> is guaranteed by design while R<sub>0,CA</sub> is determined by the user's board design.



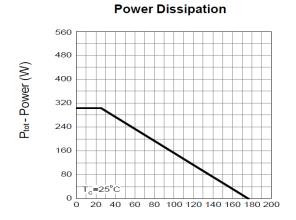
a) 40 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



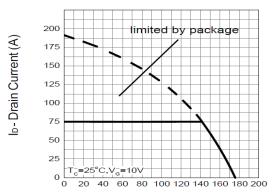
b) 62.5 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\mu s$ , Duty cycle < 2.0 %. 3. Starting T  $_J$  = 25 °C,  $\,$  L = 1 mH, I  $_{AS}$  = 36.3 A, V  $_{DD}$  = 100 V, V  $_{GS}$  = 10 V.

### **Typical Operating Characteristics**



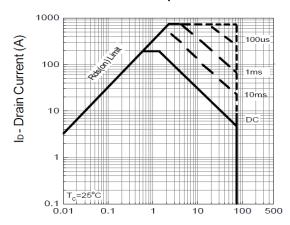
#### **Drain Current**



T<sub>c</sub>- Case Temperature (°C)

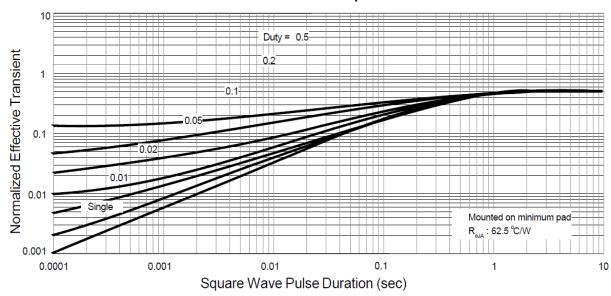
T<sub>c</sub>-Case Temperature (°C)

#### Safe Operation Area



V<sub>DS</sub> - Drain - Source Voltage (V)

#### Thermal Transient Impedance

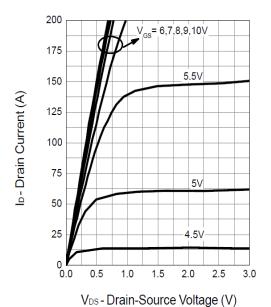


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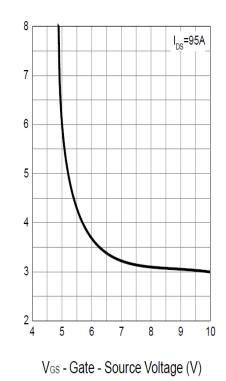
### **Typical Operating Characteristics (Cont.)**





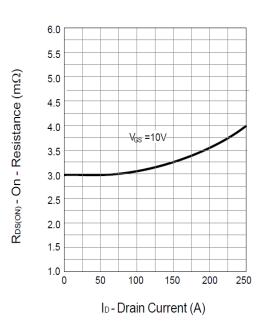
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#### **Drain-Source On Resistance**

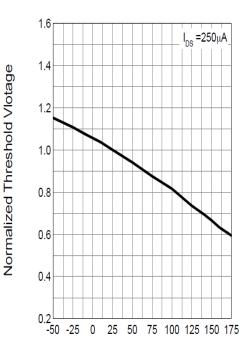


RDS(ON) - On - Resistance (m\Omega)

#### **Drain-Source On Resistance**

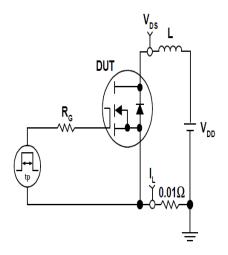


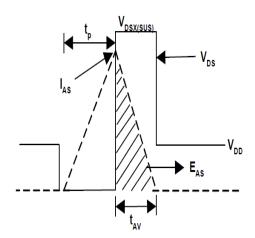
### **Gate Threshold Voltage**



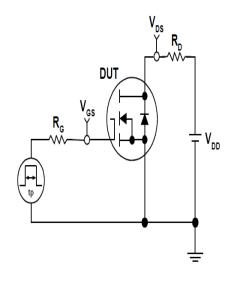
T<sub>j</sub> - Junction Temperature (°C)

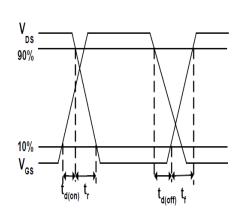
### **Avalanche Test Circuit and Waveforms**



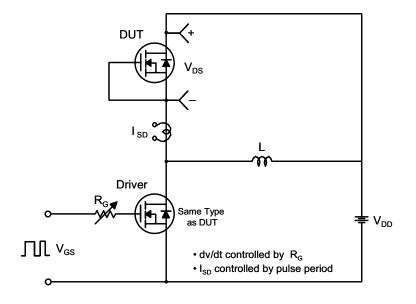


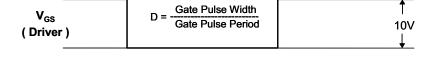
## **Avalanche Test Circuit and Waveforms**

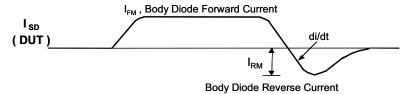


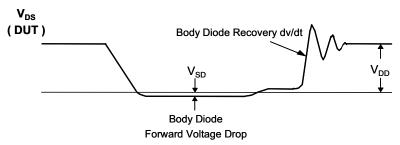


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms









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